Highly efficient low-voltage cathodoluminescence of LaF_3 : Ln^{3+} ($Ln=Eu^{3+}, Ce^{3+}, Tb^{3+}$) spherical particles

Zhen-Ling Wang,^{1,2} H. L. W. Chan,¹ Hiu-Ling Li,¹ and J. H. Hao^{1,a)} ¹Department of Applied Physics, The Hong Kong Polytechnic University, Hong Kong, People's Republic of China ²Analytical and Testing Center, Zhoukou Normal University, Zhoukou 466000, People's Republic of China

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Spherical particles of rare-earth doped LaF₃ are synthesized through refluxing in glycerol/water media. The low-voltage cathodoluminescence of LaF₃:Eu due to ${}^{5}D_{0} \rightarrow {}^{7}F_{1}$ and ${}^{5}D_{0} \rightarrow {}^{7}F_{2}$ transitions was found to be sensitive to the site that Eu³⁺ ions occupied. The luminous efficiency of LaF₃:Ce³⁺, Tb³⁺ with green emission is improved from 1.53 to 2.02 lm/W compared with LaF₃:Tb³⁺, due to the energy transfer processes from Ce³⁺ to Tb³⁺ ions. Our results suggest that the obtained spherical particles of rare-earth doped LaF₃ are promising as highly efficient low-voltage cathodoluminescent phosphors, which have received considerably less attention. © 2008 American Institute of Physics. [DOI: 10.1063/1.2998582]

The phenomenon of cathodoluminescence (CL) is related to the emission of light in response to the excitation of matter with accelerated electrons. As an electron-beam excitation may produce orders-of-magnitude greater carrier generation rates than optical excitation, it is especially advantageous in studies of wide bandgap materials. Moreover, the CL properties of materials are critical for field-emission displays (FEDs), which are promising emissive displays realizing high resolution and low consumption of electric power.¹ Phosphors used in FEDs require several new properties that the traditional cathode-ray tube (CRT) display phosphors may not possess, such as high CL efficiency under low excitation voltage (≤ 5 kV) and specific surface conditions.² Much work has been done to explore low-voltage cathodoluminescent phosphors for FED application.^{3–5}

Fluorides are advantageous as luminescent host materials owing to their wide bandgap, low vibrational energies, and the subsequent minimization of the quenching of the excited state of the rare-earth ions.⁶ Rare-earth doped fluorides have extensively been studied in the applications of vacuum ultraviolet optics, upconverters, biological fluorescent labels, and so on.^{7–9} However, a few papers has been reported on the CL of fluorides, limited to CeF₃ crystals, rare-earth-activated binary fluoride crystals and Zr–Ba–La–Al–Na fluoride glass.^{10–12} In particular, the characteristic of low-voltage CL in fluorides is unknown. The LaF₃ compound has the photochemical stability and its phonon energy is as low as 350 cm⁻¹. In this letter, the low-voltage CL properties of LaF₃:Eu³⁺, LaF₃:Tb³⁺, and LaF₃:Ce³⁺, Tb³⁺ spherical particles are reported. Excellent performance of low-voltage CL for the phosphors is determined.

LaF₃:20% Eu³⁺, LaF₃:10% Tb³⁺, and LaF₃:20% Ce³⁺, 10% Tb³⁺ spherical particles were prepared by mixing lanthanide trichlorides with NH₄F in glycerol/water media and refluxing at boiling state (110 °C) for 2 h. The solid was separated by centrifugation, cleaned, and dried at 90 °C for 12 h. Then the as-prepared samples were annealed at 600 °C for 4 h. The commercial CRT phosphors Y_2O_2S : Eu (red) and ZnS:Cu (green) were provided by Shanghai Yuelong New Materials Co. for comparison. The details of measurements were described in our recent work.¹³

After annealing at 600 °C, the x-ray diffraction (XRD) patterns indicate that LaF₃: Eu³⁺, LaF₃: Tb³⁺, and LaF₃: Ce³⁺, Tb³⁺ particles are basically in agreement with the hexagonal structure known from bulk LaF₃ (Fig. 1). The rare-earth ions (Eu³⁺, Ce³⁺, Tb³⁺) were doped into the LaF₃ lattice and occupied the site of La^{3+} ions, with the formation of a $La_{1-r}Ln_rF_3$ solid solution even at relatively higher Ln^{3+} doping concentration, except those two very weak peaks arising from CeO₂ (Ref. 15) for LaF₃:20% Ce³⁺: 10%Tb³⁺ sample [denoted as * in Fig. 1(d)]. The typical scanning electron microscopy (SEM) image of LaF₃:Eu³⁺ sample is shown in Fig. 2. LaF₃:Eu³⁺ powders annealed at 600 °C are composed of spherical or near spherical particles with size around 300 nm (Fig. 2, inset). The morphologies of $LaF_3:Tb^{3+}$ and $LaF_3:Ce^{3+}$, Tb^{3+} particles are similar to that of LaF₃:Eu³⁺ particles, which indicated that the spherical morphology was not evidently affected by categories of doping lanthanide ions. Phosphors with submicron-scale spherical morphology are important for displays because they offer higher packing density, lower scattering of light, brighter lu-



FIG. 1. XRD patterns of (b) LaF₃: Eu³⁺, (c) LaF₃: Tb³⁺, (d) LaF₃: Ce³⁺, Tb³⁺ particles, and (a) the standard data for bulk LaF₃ (Ref. 14).

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^{a)}Author to whom correspondence should be addressed. Electronic mail: apjhhao@polyu.edu.hk.



FIG. 2. SEM images of LaF₃: Eu³⁺ particles annealed at 600 $^{\circ}$ C (inset is the enlarged image of the same sample).

minescent performance, and more improved screen packing. 5,13

Under the excitation of low-voltage electron beam, LaF₃:Eu³⁺ particles exhibit orange-red emission of Eu³⁺ ions. The CL spectra are composed of the characteristic line emissions arising from the ${}^{5}D_{0} \rightarrow {}^{7}F_{J}$ and ${}^{5}D_{1} \rightarrow {}^{7}F_{J}$ transitions of the Eu³⁺ ions [Fig. 3(a)]. The relative intensities of the ${}^{5}D_{0} \rightarrow {}^{7}F_{1}$ and ${}^{5}D_{0} \rightarrow {}^{7}F_{2}$ emissions were found to be



FIG. 3. (Color online) CL spectra of (a) $\rm Eu^{3+}$ and (b) $\rm Tb^{3+}$ ions in $\rm LaF_3$ particles.

very sensitive to the site that Eu³⁺ ions occupied. As for $LaF_3:Eu^{3+}$ particles, the Eu^{3+} ions occupy the La^{3+} ion lattice and are at a site with inversion symmetry in the LaF₃ matrix; thus the dominating emission centered at 590 nm corresponds to the ${}^{5}D_{0} \rightarrow {}^{7}F_{1}$ magnetic dipole transition.¹⁶ The CL spectrum of the sample annealed at 600 °C [solid line in Fig. 3(a) is markedly strengthened compared with that of the as-prepared sample [dotted line in Fig. 3(a)]. At 4.0 kV and 91.6 μ A/cm², the luminance values of the asprepared and annealed samples are 25 and 835 cd/m², respectively. The luminous efficiency is improved from 0.02 to 0.72 lm/W after annealing treatment, which is still poorer than 9.20 lm/W of commercial Y₂O₂S: Eu phosphor. Annealing treatment at high temperature makes the crystallite size increase and the number of atoms in the grain boundaries and on the surface decrease, leading to an increase in the number of radiative recombination sites and therefore a higher probability of radiative recombination.

LaF₃ particles doped with Tb³⁺ and codoped with Ce³⁺, Tb³⁺ ions show green emission under the excitation of lowvoltage electron beam. The CL spectra of these two samples annealed at 600 °C are similar in profile, which are arising from the transitions between the excited ${}^{5}D_{4}$ state and the ${}^{7}F_{J}$ (J=6-3) ground states of Tb³⁺ ions [Fig. 3(b)]. However, the CL intensity of LaF₃:Ce³⁺, Tb³⁺ particles (dotted line) is improved by 17% with respect to that of LaF_3 : Tb³⁺ particles (solid line). Correspondingly, the luminance value is increased from 2300 to 3036 cd/m², and the luminous efficiency is improved from 1.53 to 2.02 lm/W (4.0 kV, 117.5 μ A/cm²). This indicates that the Tb³⁺ green emission in LaF_3 : Ce³⁺, Tb³⁺ particles can be enhanced by the energy transfer processes from Ce³⁺ to Tb³⁺ ions. For cursory comparison, the following data of luminance or luminous efficiency from other hosts are presented: (a) 171 cd/m^2 at 3 kV and 500 μ A/cm² for YAG:Tb (YAG denotes yttrium aluminum garnet) powder prepared by combustion synthesis and annealed at 1600 °C,¹⁷ (b) 0.70 lm/W at 5 kV and 57 μ A/cm² for ZnAl₂O₄: Tb prepared by spray pyrolysis and annealed at 1600 °C,¹⁸ (c) 0.54 lm/W at 5 kV for Ba₂B₅O₉Cl: Tb prepared by spray pyrolysis and annealed at 630 °C,¹⁹ and (d) 9.19 lm/W at 4 kV and 110 μ A/cm² for commercial product ZnS:Cu. Some works deserve to be done in order to improve the luminous efficiency of these fluoride phosphors, such as increasing crystallinity, controlling particle size, altering doping concentration, optimizing the synthesis procedure, etc.^{20,2}

The CL intensity is dependent on measurement conditions such as current density and excitation voltage. The CL intensities of the LaF₃: Eu^{3+} particles (annealed at 600 °C) increased linearly with the applied voltage from 1.5 to 3.5 kV at a current density of 12.3 μ A/cm² [Fig. 4(a)]. According to an empirical formula,²² the electron penetration depths of LaF_3 : Eu³⁺ phosphors at the anode voltage of 1.5, 2.0, 2.5, 3.0, and 3.5 kV are estimated to be 6.1, 13.2, 24.2, 39.8, and 60.5 nm, respectively. Hence, the increase in intensity with increasing applied voltage is due to an increase in the number of excited luminescence centers resulting from an increase in electron penetration depth. The CL intensities also increase with the increasing current density from 9.9 to 26.9 μ A/cm² under fixed excitation voltage of 2.5 kV [Fig. 4(b)]. This indicates that $LaF_3:Eu^{3+}$ particles are resistant to the current saturation, which is of benefit to FEDs.

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FIG. 4. The dependence of CL intensity (592 nm) of LaF_3 : Eu³⁺ particles on the (a) excitation voltage and (b) current density.

In summary, rare-earth doped LaF₃ spherical particles were prepared by soft-chemistry method. The effect of annealing treatment, codoping, and measurement conditions on CL properties was investigated as well. The particles excited at low-voltage electron beam (4.0 kV) show high efficiencies of 0.72 and 2.02 lm/W for LaF₃:Eu³⁺ and LaF₃:Ce³⁺, Tb³⁺, respectively. Our work indicates that rare-earth doped LaF_3 is promising for low-voltage CL applications.

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